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	Class	Subclass
ISSUE CLASSIFICATION		

PATENT NUMBER

U.S. UTILITY Patent Application

O.I.P.E.

PATENT DATE

~~SCANNED~~

Q.4

APPLICATION NO. 09/931997	CONT/PRIOR F	CLASS 250	SUBCLASS 559.4	ART UNIT 2878	EXAMINER PVO
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APPLICANTS

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Method and its apparatus for inspecting particles or defects of a semiconductor device

TITLE

PTO-2040
12/99

ISSUING CLASSIFICATION

[illegible]

<input type="checkbox"/> TERMINAL DISCLAIMER	DRAWINGS			CLAIMS ALLOWED	
	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G.
<input type="checkbox"/> The term of this patent subsequent to _____ (date) has been disclaimed. <input type="checkbox"/> The term of this patent shall not extend beyond the expiration date of U.S Patent. No. _____ <input type="checkbox"/> The terminal _____ months of this patent have been disclaimed.	_____ (Assistant Examiner) (Date)			NOTICE OF ALLOWANCE MAILED	
	_____ (Primary Examiner) (Date)			ISSUE FEE	
				Amount Due	Date Paid
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